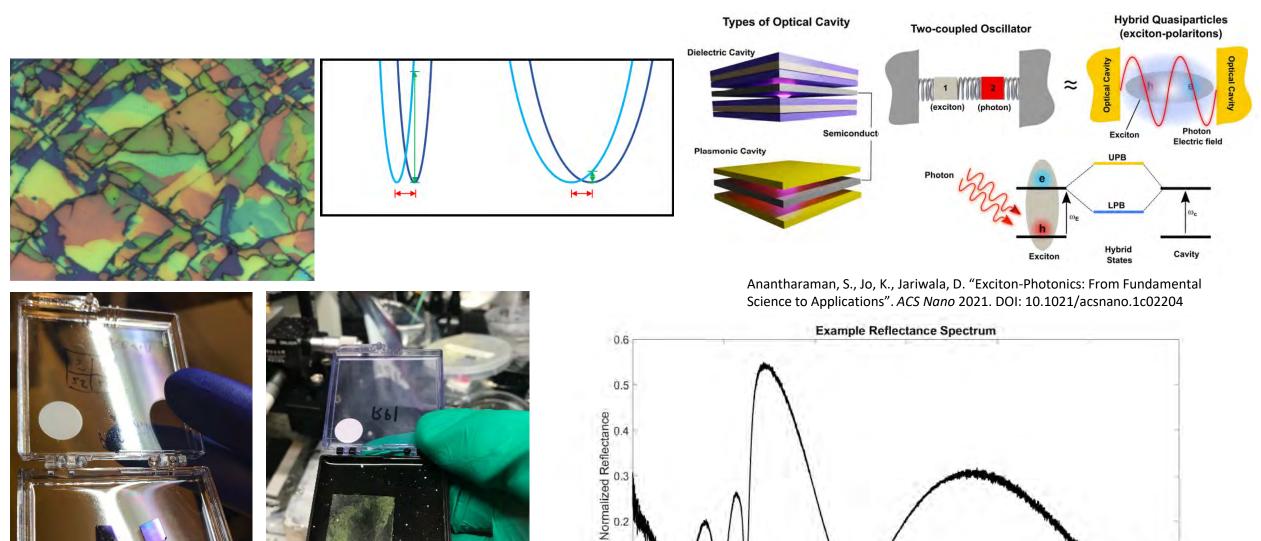
Effects of Polystyrene Coating on the Reflectance Spectra of Quasi-2D Perovskite Flakes

Kevin Li (SUNFEST REU), Electrical Engineering, Georgia Tech Mentor: Dr. Surendra Anantharaman, PI: Dr. Deep Jariwala, Materials Science and Engineering

Background: Perovskite Flakes, Sensor Application



0.1

UPB HO

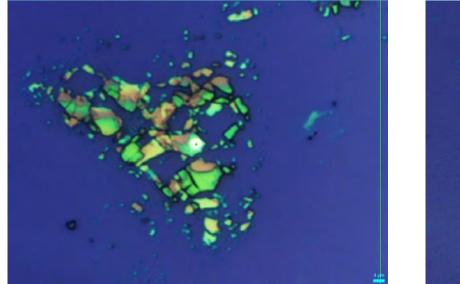
0 400 500 600 700 800 900 1000 Wavelength (nm)

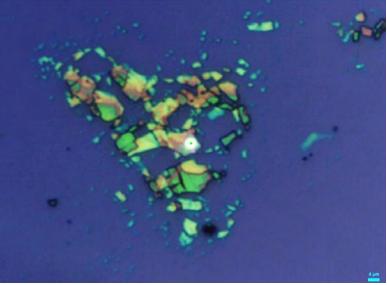
LPB

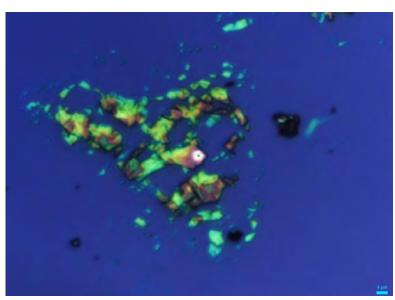
1

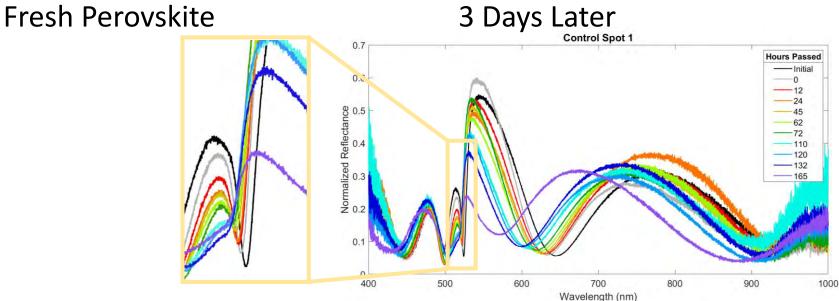
Unprotected Perovskite over Time

Problem: degradation in oxygen







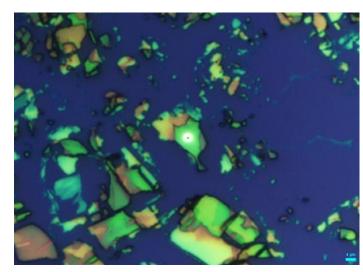


7 Days Later

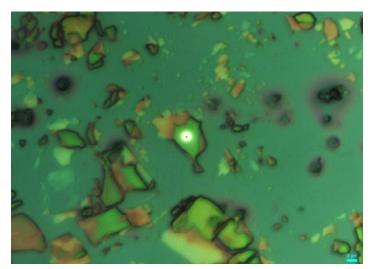
Approach: Polystyrene Coating

• Spin coating at various RPMs (revolutions per minute)

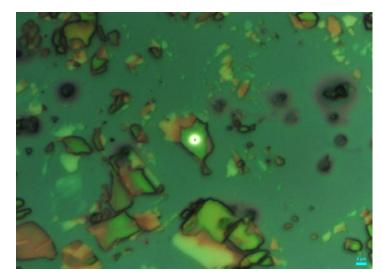




Fresh RP1



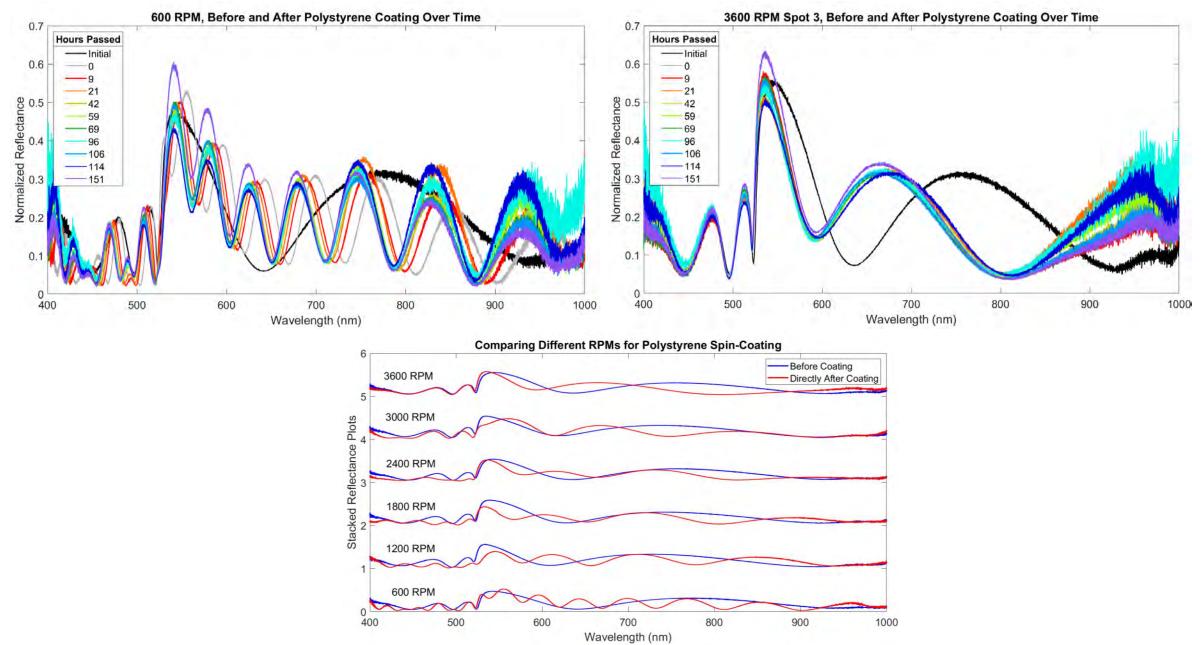
Directly after applying polystyrene coating



7 days later

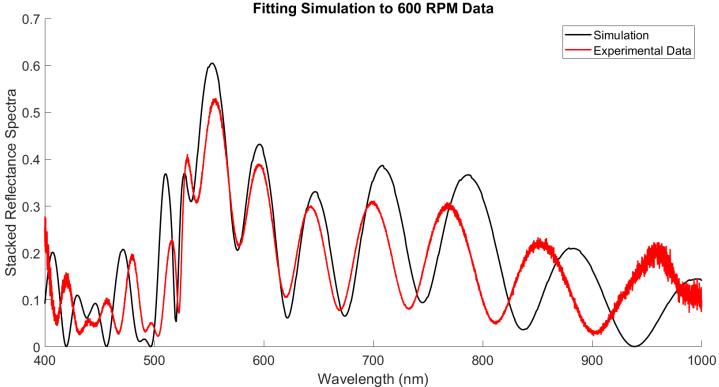
(Left outside to be exposed to air between measurements)

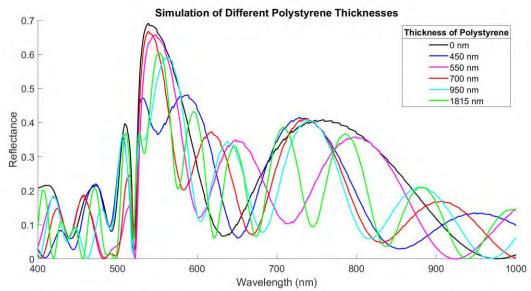
Results: Varying Amounts of Change



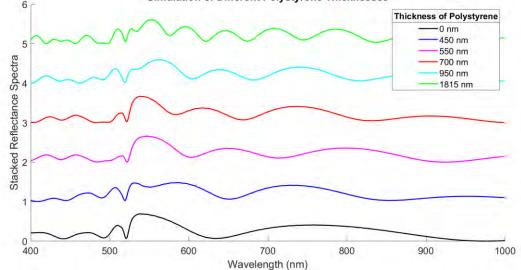
Simulation Analysis

RPM	Sim-Suggested Polystyrene Thickness (nm)
600	~1815
1200	~900 to 975
1800	~700
2400	~500 to 600
3000	~550
3600	~415 to 525

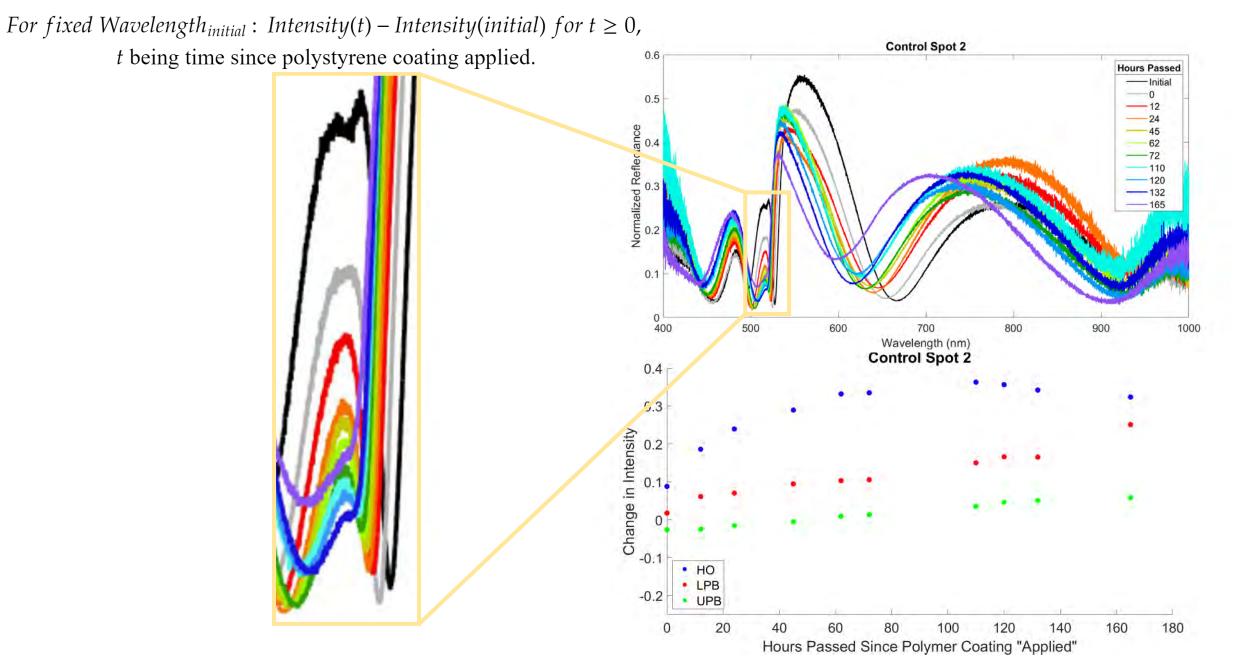




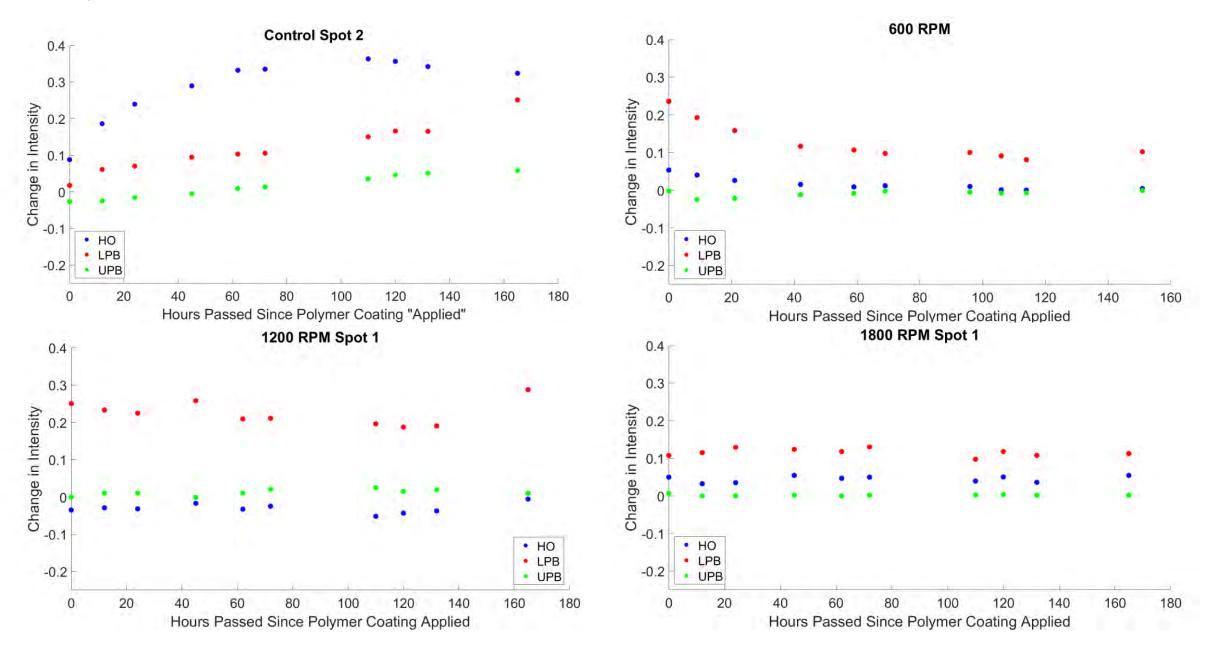
Simulation of Different Polystyrene Thicknesses



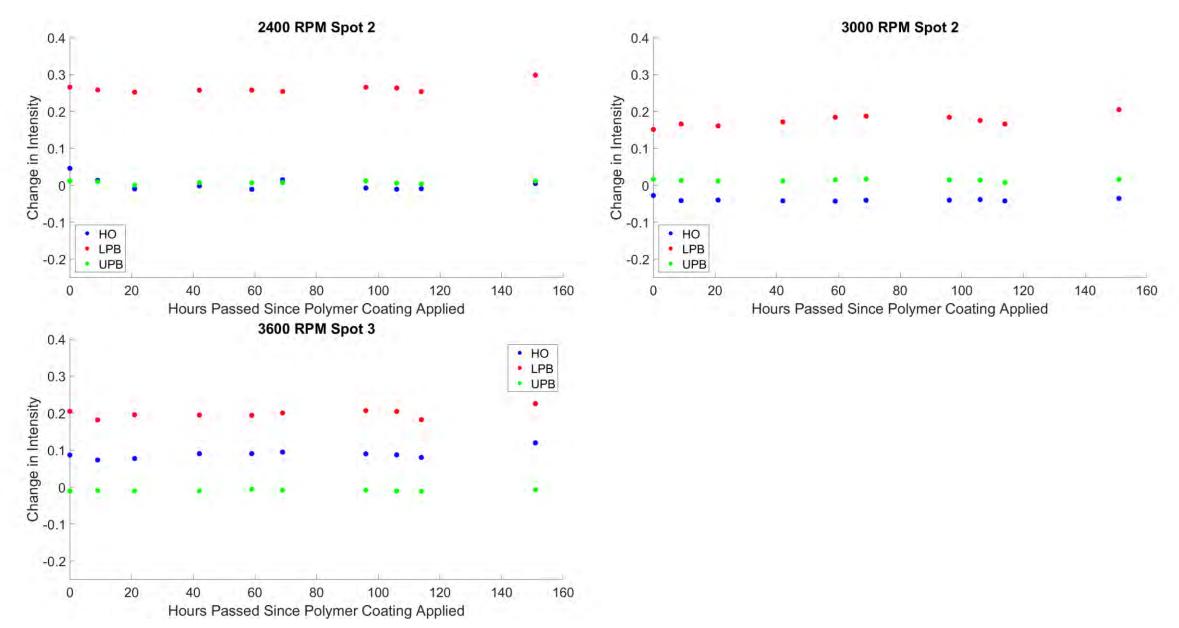
Change in Intensity of Unencapsulated RP1/300nm SiO₂/Si



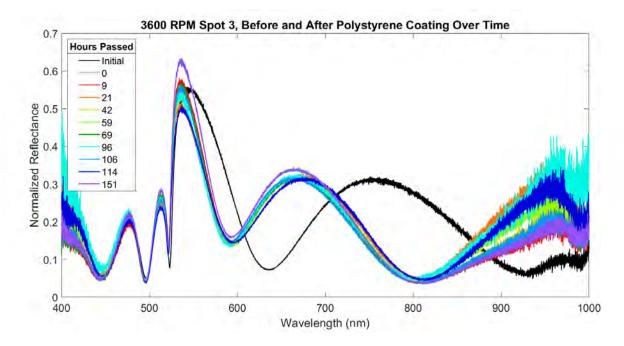
Comparison Between Control and Different RPMs

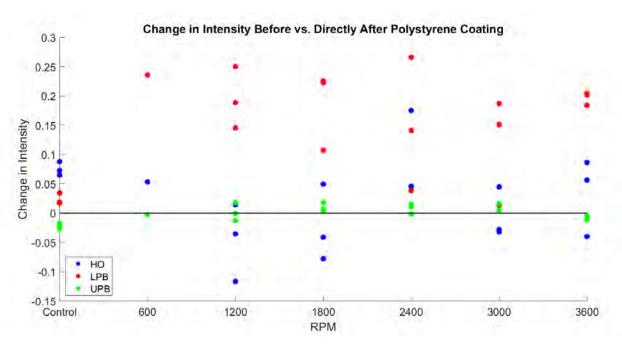


Comparison Between Control and Different RPMs Cont.

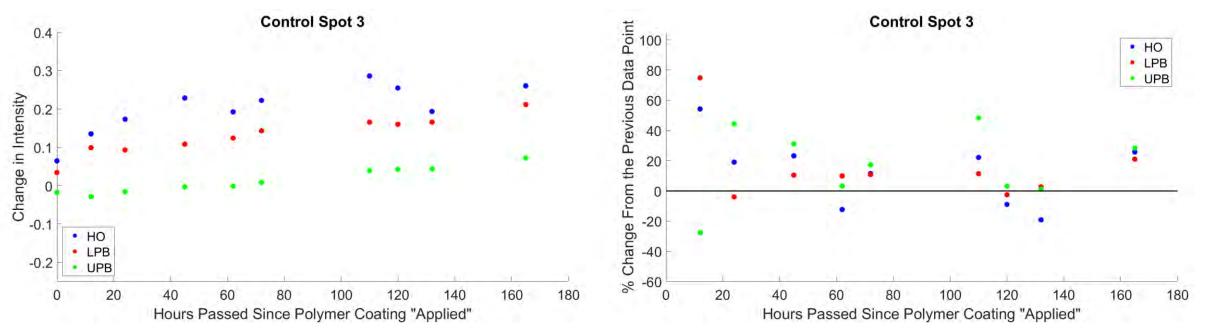


Additional Cavity Modes Upon Polymer Coating



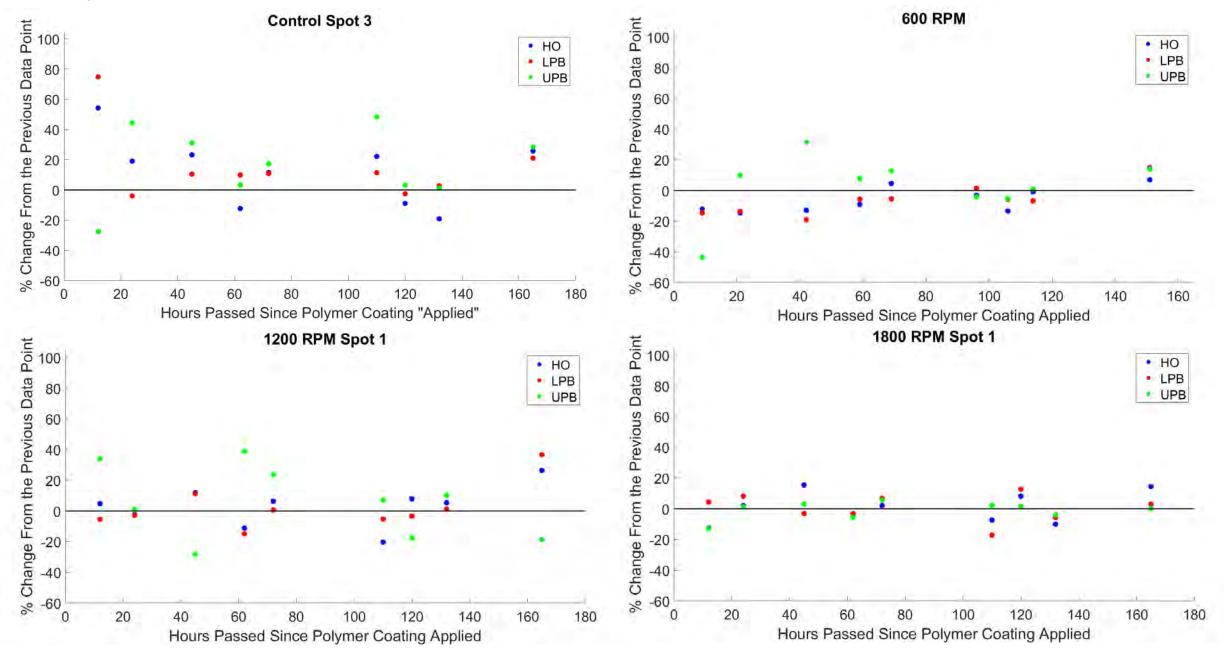


Now, Percent Change in Intensity of HO, UPB, LPB

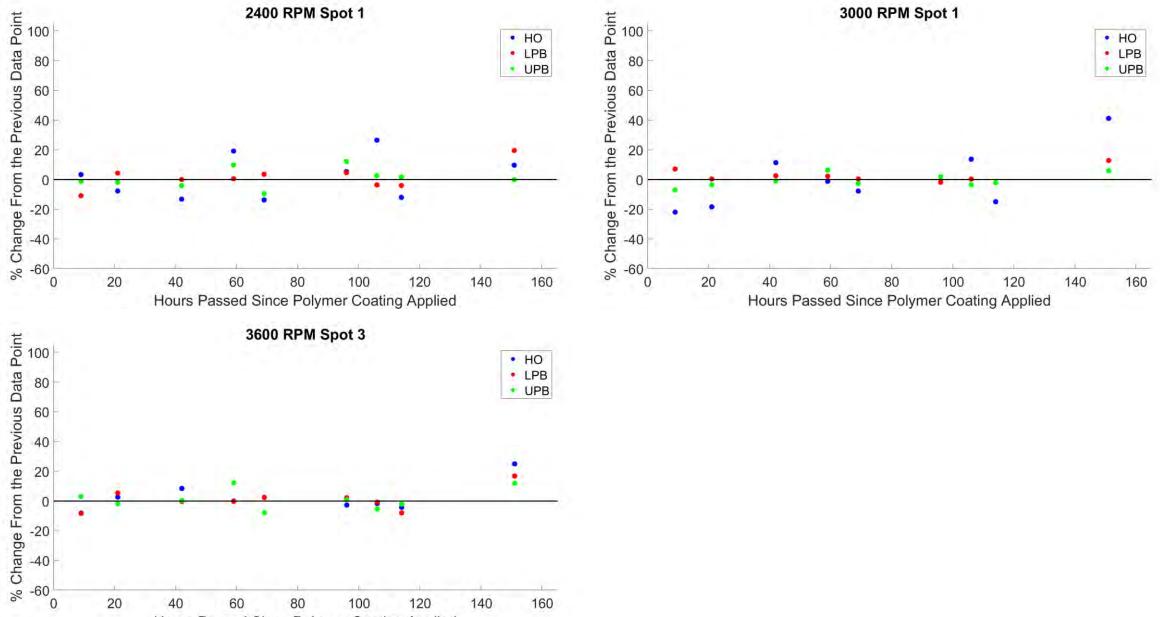


$$\frac{Intensity(t_n) - Intensity(t_{n-1})}{Intensity(t_{n-1})} \times 100$$

Comparison Between Control and Different RPMs

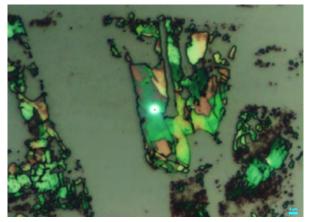


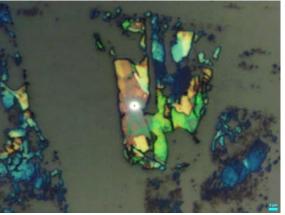
Comparison Between Control and Different RPMs Cont.

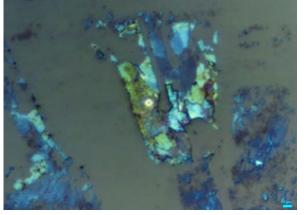


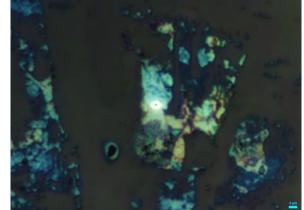
Hours Passed Since Polymer Coating Applied

A Sample of PVD Al₂O₃ on RP1 Over Time







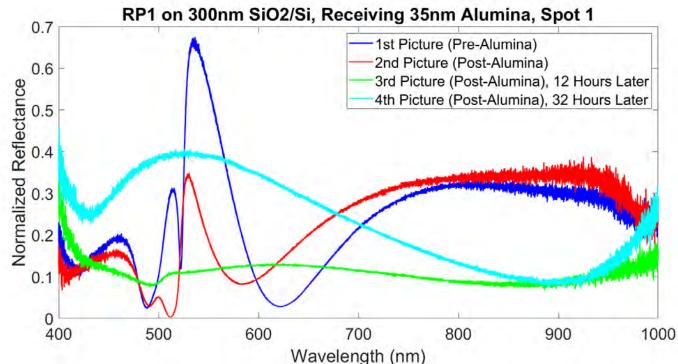


Fresh RP1

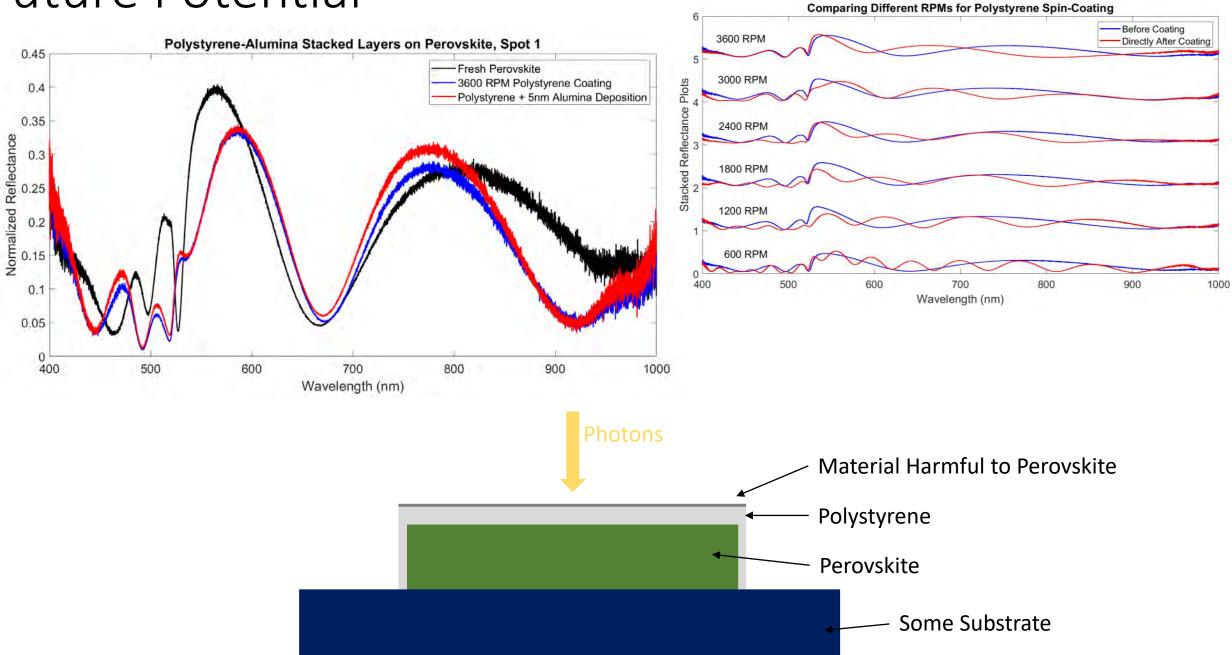
Within 2 hours of alumina deposition

12 hours after deposition

32 hours after deposition



Future Potential



Acknowledgements

- Mentor: Dr. Surendra Anantharaman
- PI: Dr. Deep Jariwala
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